



Non-Contact Sheet Resistance Mapper

DATA SHEET - EddyCus[®] TF map 2020SR

The EddyCus[®] TF map 2020SR is a fast non-contact sheet resistance mapping system for conductive thin films, and also for layer thickness mapping of metal films. Typical applications are the quality assurance of TCOs, metals films, graphene, CNT and metal nano wires or grids. The system is highly beneficial for the quality assessment of deposition, annealing, and doping processes. The EddyCus[®] TF map 2020SR allows a quick mapping of samples sizes up to 8 inches. The measured values are immediately displayed in the easy to handle software. Its compact graphical user interface and its various easy to use analysis functions enable to obtain a

quick overview as well as to run a fast analysis and evaluation of the measured results within one step. Additionally, the mapping module allows a freehand selection of areas in order to analyze the sheet resistance in certain areas of interest. These mappings can also be well analyzed by histogram evaluation. Furthermore, the software supports statistical analysis, or color coding for analyzing local defects, and it provides data export functions. The EddyCus[®] TF map 2020SR is an accurate mapping system valuable for many applications dedicated to cater the needs of R&D centers, quality assurance departments and research institutes.

SURAGUS GmbH
Maria-Reiche-Str. 1
01109 Dresden
Germany

E-Mail: info@suragus.com

Phone: +49 (0) 351 273 598 01
Fax: +49 (0) 351 329 920 58

www.suragus.com
www.sheet-resistance-measurement.com

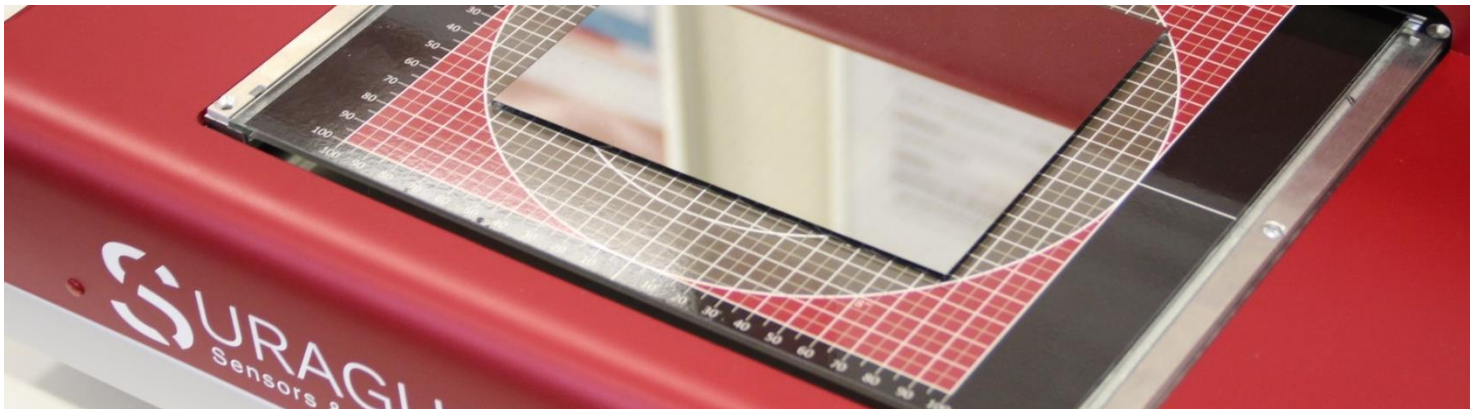
Testing of
conductive layers.



Certified
ISO 9001

DATA SHEET

EddyCus® TF map 2020SR – Sheet Resistance Mapping



EddyCus® TF map 2020SR

Sheet resistance & metal thickness measurement

Substrate thickness measurement

Max. scanning area

Max. sample thickness
(defines distances)

Sheet resistance range

Scanning time @ 1mm measurement pitch

Thickness mapping of metal films (e.g. copper)

Scanning pitch

Device size (w/h/d)

Weight

Available features

Non-contact eddy current sensor

Ultrasonic sensor

8 inch / 200 x 200 mm² (larger on request)

2 / 5 / 10 mm (other on request)
(defined by the thickest sample)

0.001 – 10 Ohm/sq < 2% accuracy
10 – 100 Ohm/sq < 3% accuracy
100 – 1,000 Ohm/sq < 5% accuracy

100 x 100 mm² less than 3 minutes
200 x 100 mm² less than 5 minutes

1 nm – 500 µm (in accordance with sheet resistance range)

0.025 – 2.5 mm

498 x 212 x 656 mm

22.5 kg

Anisotropy sensor / optical transmission sensors

THIN FILM CHARACTERIZATION

Characterization Mode

- Non-contact sheet resistance mapping of conductive thin films [Ohm/sq]
- Non-destructive layer thickness mapping of metal films [nm, µm]

Benefits

- + Sheet resistance mapping of encapsulated layers
- + Quick sheet resistance measurement of small sample sizes up to 8 inches

SOFTWARE & HANDLING

Sheet Resistance Analyzer 2.0

- Very easy to use software
- Instant graphical display of measurement and mapping
- Freehand marking of mappings for a detailed analysis

